

SAND2015-10729C

# Low-Level Track Finding and Completion using Random Fields

Tu-Thach Quach    Rebecca Malinas    Mark W. Koch

Sandia National Laboratories

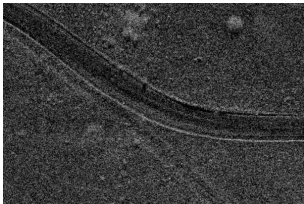
February 18, 2016



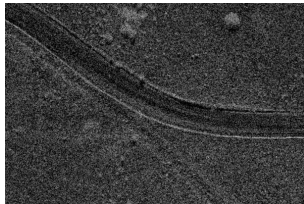
Sandia National Laboratories is a multi-program laboratory managed and operated by Sandia Corporation, a wholly owned subsidiary of Lockheed Martin Corporation, for the U.S. Department of Energy's National Nuclear Security Administration under contract DE-AC04-94AL85000.

# Coherent Change Detection (CCD) Image

Morning

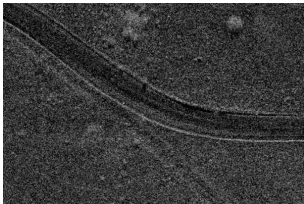


Afternoon



# Coherent Change Detection (CCD) Image

Morning



Afternoon



# Algorithm

- 1 Compute ridge feature  $\lambda_i$  for each pixel  $i$  in input image  $I$

# Algorithm

- 1 Compute ridge feature  $\lambda_i$  for each pixel  $i$  in input image  $I$
- 2 Form binary image  $I_{bw}$  by thresholding  $\lambda_i$ :  $I_{bw}(i) = 1$  if  $\lambda_i > \tau$

# Algorithm

- 1 Compute ridge feature  $\lambda_i$  for each pixel  $i$  in input image  $I$
- 2 Form binary image  $I_{bw}$  by thresholding  $\lambda_i$ :  $I_{bw}(i) = 1$  if  $\lambda_i > \tau$
- 3 Thin, branch, linearize  $I_{bw}$

# Algorithm

- 1 Compute ridge feature  $\lambda_i$  for each pixel  $i$  in input image  $I$
- 2 Form binary image  $I_{bw}$  by thresholding  $\lambda_i$ :  $I_{bw}(i) = 1$  if  $\lambda_i > \tau$
- 3 Thin, branch, linearize  $I_{bw}$
- 4 Form CDT graph using obtained tracks as *constrained* edges

# Algorithm

- 1 Compute ridge feature  $\lambda_i$  for each pixel  $i$  in input image  $I$
- 2 Form binary image  $I_{bw}$  by thresholding  $\lambda_i$ :  $I_{bw}(i) = 1$  if  $\lambda_i > \tau$
- 3 Thin, branch, linearize  $I_{bw}$
- 4 Form CDT graph using obtained tracks as *constrained* edges
- 5 Optimize energy function:

$$\sum_{i \in E} f_i(x_i) + \sum_{i,j \in N} [x_i \neq x_j][i \in E_C \vee j \in E_C] g_{ij}(x_i, x_j)$$



## Forming Initial Binary Image

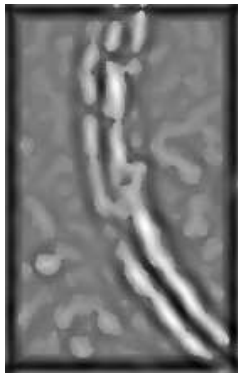


Input CCD Image

## Forming Initial Binary Image



Input CCD Image



Ridge Feature

## Forming Initial Binary Image



Input CCD Image

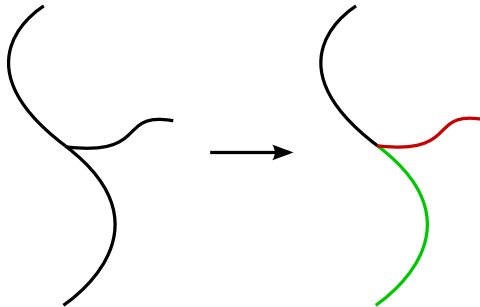


Ridge Feature

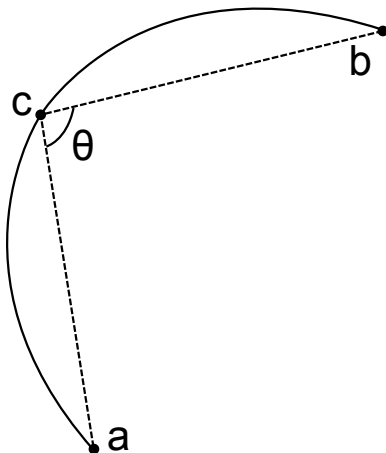


Thresholded Image

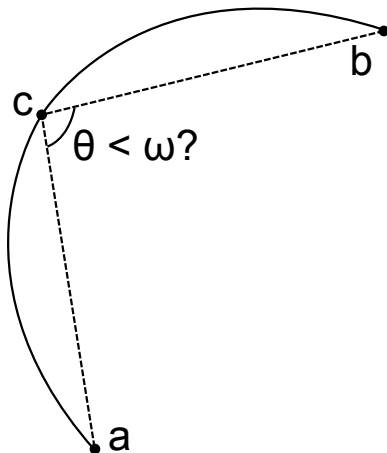
# Branching



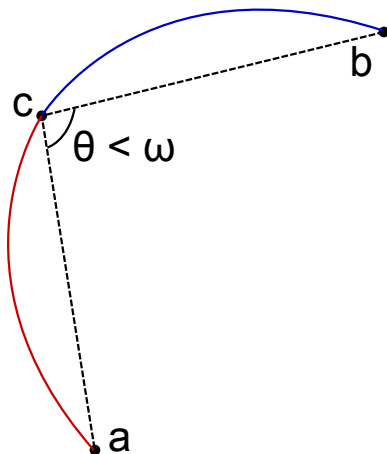
# Linearization



# Linearization



# Linearization

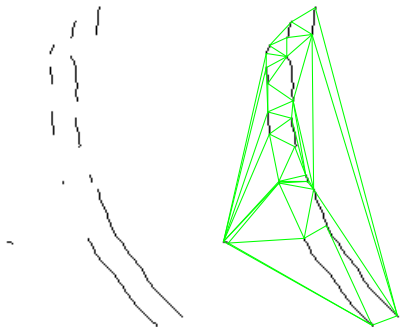


# Constrained Delaunay Triangulation (CDT) Graph

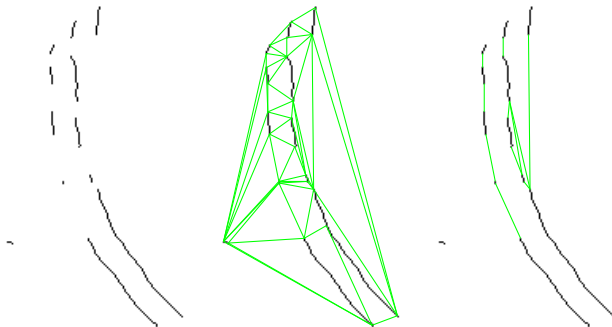




# Constrained Delaunay Triangulation (CDT) Graph



# Constrained Delaunay Triangulation (CDT) Graph



# Optimization

$E$ : edges of CDT graph

$E_C \subset E$ : constrained edges

$N \subset E \times E$ : neighborhood system

# Optimization

$E$ : edges of CDT graph

$E_C \subset E$ : constrained edges

$N \subset E \times E$ : neighborhood system

Minimize binary energy function ( $x_i \in \{0, 1\}$ ):

$$\sum_{i \in E} \underbrace{f_i(x_i)}_{\text{Unary}} + \sum_{i, j \in N} \underbrace{[x_i \neq x_j][i \in E_C \vee j \in E_C]g(i, j)}_{\text{Pairwise}}$$

## Unary Cost

$\mathcal{P}(i)$ : set of pixels corresponding to edge  $i$

$\lambda^i = \frac{1}{|\mathcal{P}(i)|} \sum_{j \in \mathcal{P}(i)} \lambda_j$ : average ridge feature along edge  $i$

$$f_i(x_i) = -\log p(\lambda^i | x_i)$$

# Unary Cost

$\mathcal{P}(i)$ : set of pixels corresponding to edge  $i$

$\lambda^i = \frac{1}{|\mathcal{P}(i)|} \sum_{j \in \mathcal{P}(i)} \lambda_j$ : average ridge feature along edge  $i$

$$f_i(x_i) = -\log p(\lambda^i | x_i)$$

By central limit theorem,

$$p(\lambda^i | x_i = 0) \approx \mathcal{N}(\mu_0, \sigma_0 / \sqrt{|\mathcal{P}(i)|}),$$

$$p(\lambda^i | x_i = 1) \approx \mathcal{N}(\mu_1, \sigma_1 / \sqrt{|\mathcal{P}(i)|}),$$

$\mu_0$  and  $\sigma_0$ : mean and standard deviation of background ridge feature

$\mu_1$  and  $\sigma_1$ : mean and standard deviation of track ridge feature

# Pairwise Cost

$\theta_{ij}$ : angle formed by edges  $i$  and  $j$

$$g(i, j) = \frac{\alpha}{1 + \exp(-\beta(\theta_{ij} - \theta_0))}$$

# Pairwise Cost

$\theta_{ij}$ : angle formed by edges  $i$  and  $j$

$$g(i, j) = \frac{\alpha}{1 + \exp(-\beta(\theta_{ij} - \theta_0))}$$

Edges with large angles should have the same class



# Sub-Modular Energy Function

Minimize binary energy function:

$$\sum_{i \in E} f_i(x_i) + \sum_{i,j \in N} [x_i \neq x_j][i \in E_C \vee j \in E_C]g(i,j)$$

# Sub-Modular Energy Function

Minimize binary energy function:

$$\sum_{i \in E} f_i(x_i) + \sum_{i,j \in N} [x_i \neq x_j][i \in E_C \vee j \in E_C]g(i,j)$$

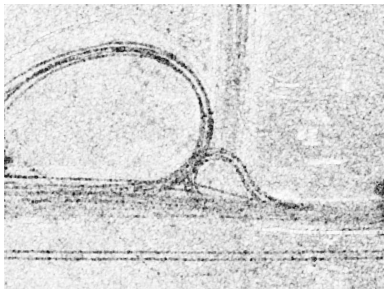
Pairwise cost is sub-modular  $\rightarrow$  global solution obtained via graph cut

Sub-modular:  $\psi(0,0) + \psi(1,1) \leq \psi(0,1) + \psi(1,0)$

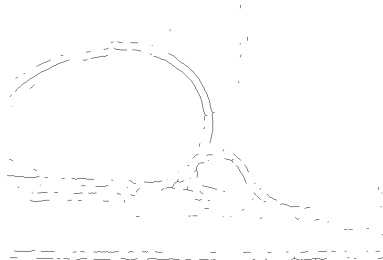
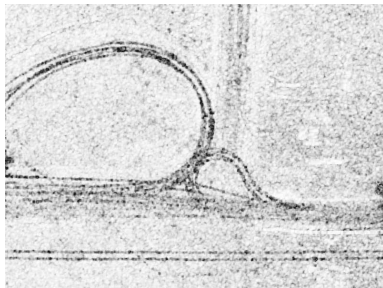
---

Kolmogorov, V., Zabih, R., "What Energy Functions Can Be Minimized via Graph Cuts," *IEEE Trans. Pattern Anal. Mach. Intell.*, 2004.

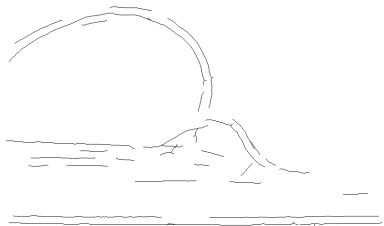
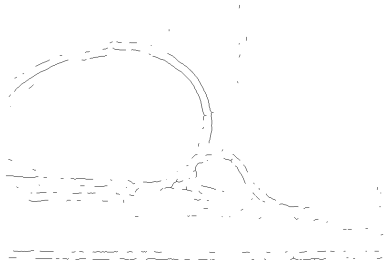
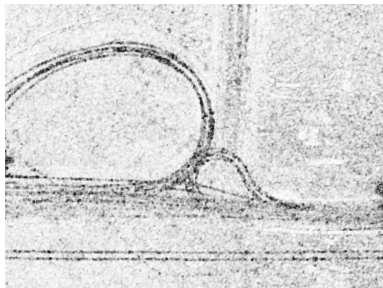
# Qualitative Results



## Qualitative Results



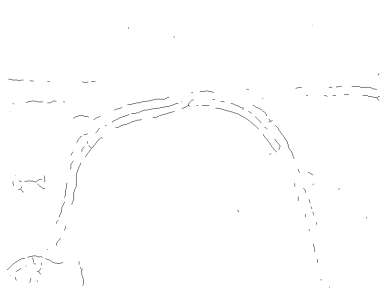
# Qualitative Results



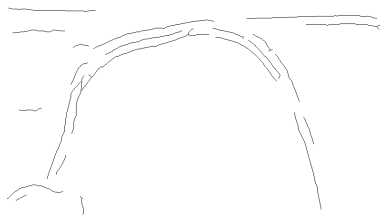
# Qualitative Results



## Qualitative Results



## Qualitative Results

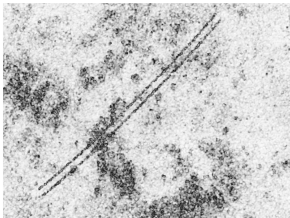




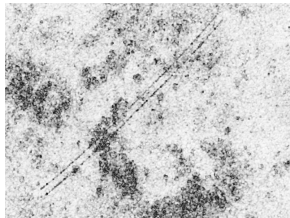
# Quantitative Results

Data sets:

Dark



Medium



Accuracy:

$$\frac{TP}{GT + FA}$$

## Quantitative Results

	Model-Based <sup>1</sup>	Current
<i>dark</i>	0.9767	<b>0.9941</b>
<i>medium</i>	0.8429	<b>0.9822</b>

---

<sup>1</sup>Quach et al., "A Model-Based Approach to Finding Tracks in SAR CCD Images," *IEEE CVPR Workshops*, 2015.

# Conclusion

- Track completion via CDT + random field is useful in completing tracks
- Approach is fast: less than 1 second on 600-by-800 image
- Future work: leverage parallel nature of tracks

Thank You

tong@sandia.gov